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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Obsolete
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	203
Number of Gates	48000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	256-BFCQFP Exposed Pad and Tie Bar
Supplier Device Package	256-CQFP (75x75)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx32-cq256b

PCI Compliance for the SX Family

The SX family supports 3.3 V and 5.0 V PCI and is compliant with the PCI Local Bus Specification Rev. 2.1.

Table 1-6 • A54SX16P DC Specifications (5.0 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V_{CCA}	Supply Voltage for Array		3.0	3.6	V
V_{CCR}	Supply Voltage required for Internal Biasing		4.75	5.25	V
V_{CCI}	Supply Voltage for I/Os		4.75	5.25	V
V_{IH}	Input High Voltage ¹		2.0	$V_{CC} + 0.5$	V
V_{IL}	Input Low Voltage ¹		-0.5	0.8	V
I_{IH}	Input High Leakage Current	$V_{IN} = 2.7$		70	μA
I_{IL}	Input Low Leakage Current	$V_{IN} = 0.5$		-70	μA
V_{OH}	Output High Voltage	$I_{OUT} = -2 \text{ mA}$	2.4		V
V_{OL}	Output Low Voltage ²	$I_{OUT} = 3 \text{ mA}, 6 \text{ mA}$		0.55	V
C_{IN}	Input Pin Capacitance ³			10	pF
C_{CLK}	CLK Pin Capacitance		5	12	pF
C_{IDSEL}	IDSEL Pin Capacitance ⁴			8	pF

Notes:

1. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
2. Signals without pull-up resistors must have 3 mA low output current. Signals requiring pull-up must have 6 mA; the latter include, FRAME#, IRDY#, TRDY#, DEVSEL#, STOP#, SERR#, PERR#, LOCK#, and, when used, AD[63::32], C/BE[7::4]#, PAR64, REQ64#, and ACK64#.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).
4. Lower capacitance on this input-only pin allows for non-resistive coupling to AD[xx].

Figure 1-9 shows the 5.0 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the A54SX16P device.

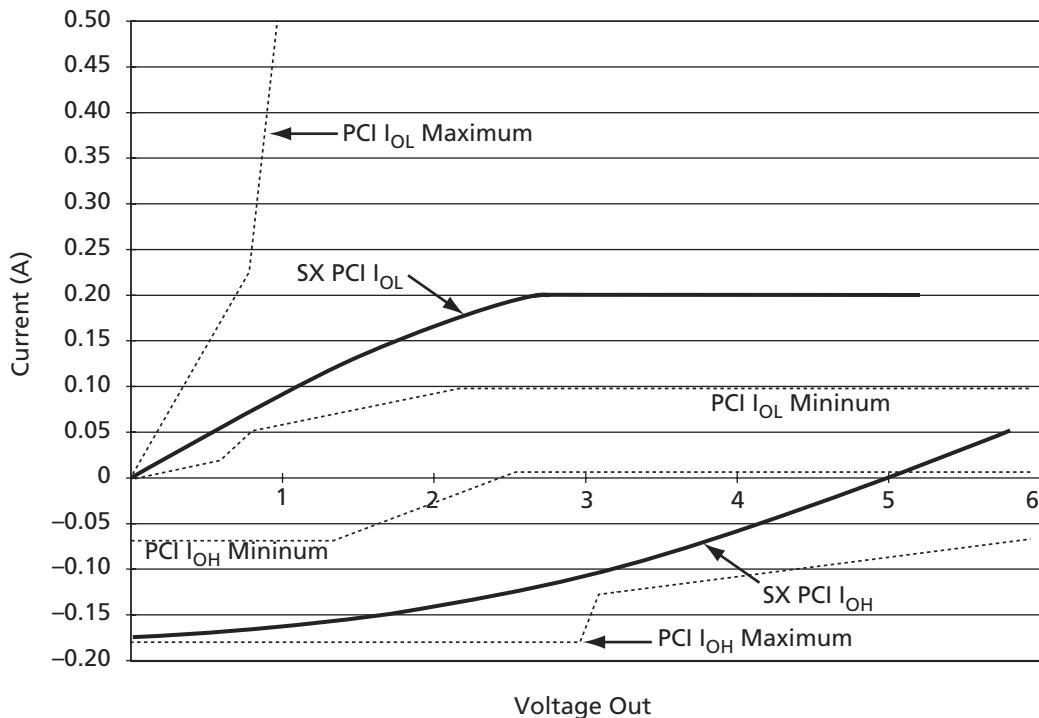


Figure 1-9 • 5.0 V PCI Curve for A54SX16P Device

$$I_{OH} = 11.9 \times (V_{OUT} - 5.25) \times (V_{OUT} + 2.45)$$

for $V_{CC} > V_{OUT} > 3.1$ V

$$I_{OL} = 78.5 \times V_{OUT} \times (4.4 - V_{OUT})$$

for $0 \text{ V} < V_{OUT} < 0.71 \text{ V}$

EQ 1-1

EQ 1-2

A54SX16P DC Specifications (3.3 V PCI Operation)

Table 1-8 • A54SX16P DC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V_{CCA}	Supply Voltage for Array		3.0	3.6	V
V_{CCR}	Supply Voltage required for Internal Biasing		3.0	3.6	V
V_{CCI}	Supply Voltage for I/Os		3.0	3.6	V
V_{IH}	Input High Voltage		$0.5V_{CC}$	$V_{CC} + 0.5$	V
V_{IL}	Input Low Voltage		-0.5	$0.3V_{CC}$	V
I_{IPU}	Input Pull-up Voltage ¹		$0.7V_{CC}$		V
I_{IL}	Input Leakage Current ²	$0 < V_{IN} < V_{CC}$		± 10	μA
V_{OH}	Output High Voltage	$I_{OUT} = -500 \mu A$	$0.9V_{CC}$		V
V_{OL}	Output Low Voltage	$I_{OUT} = 1500 \mu A$		$0.1V_{CC}$	V
C_{IN}	Input Pin Capacitance ³			10	pF
C_{CLK}	CLK Pin Capacitance		5	12	pF
C_{IDSEL}	IDSEL Pin Capacitance ⁴			8	pF

Notes:

1. This specification should be guaranteed by design. It is the minimum voltage to which pull-up resistors are calculated to pull a floated network. Applications sensitive to static power utilization should assure that the input buffer is conducting minimum current at this input voltage.
2. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).
4. Lower capacitance on this input-only pin allows for non-resistive coupling to AD[xx].

Figure 1-10 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the A54SX16P device.

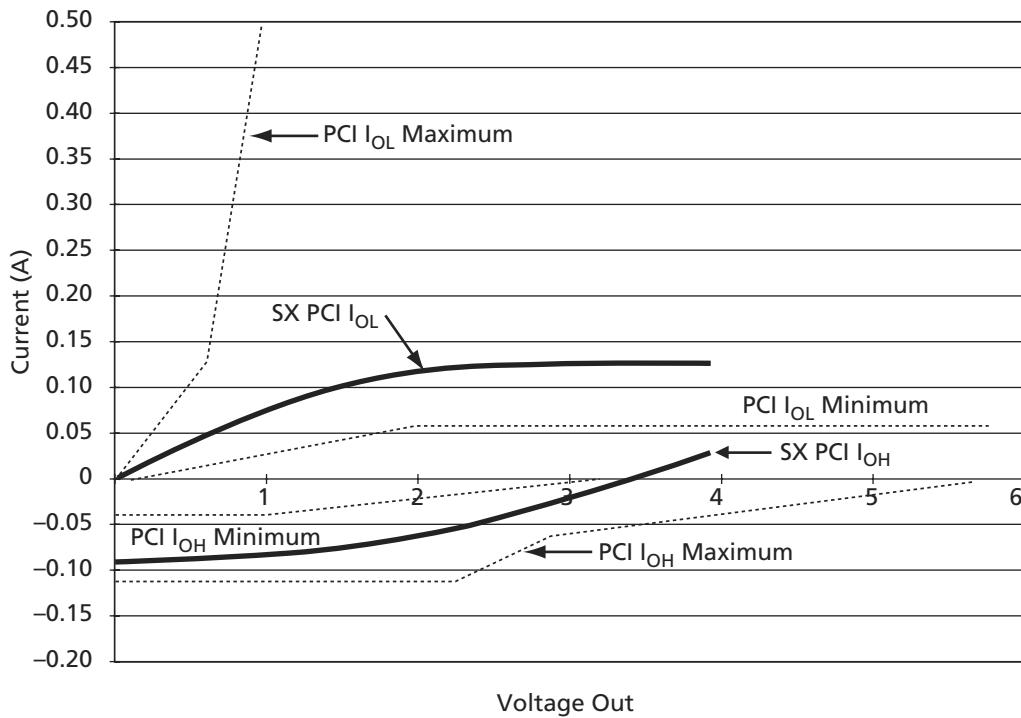


Figure 1-10 • 3.3 V PCI Curve for A54SX16P Device

$$I_{OH} = (98.0V_{CC}) \times (V_{OUT} - V_{CC}) \times (V_{OUT} + 0.4V_{CC})$$

for $V_{CC} > V_{OUT} > 0.7 V_{CC}$

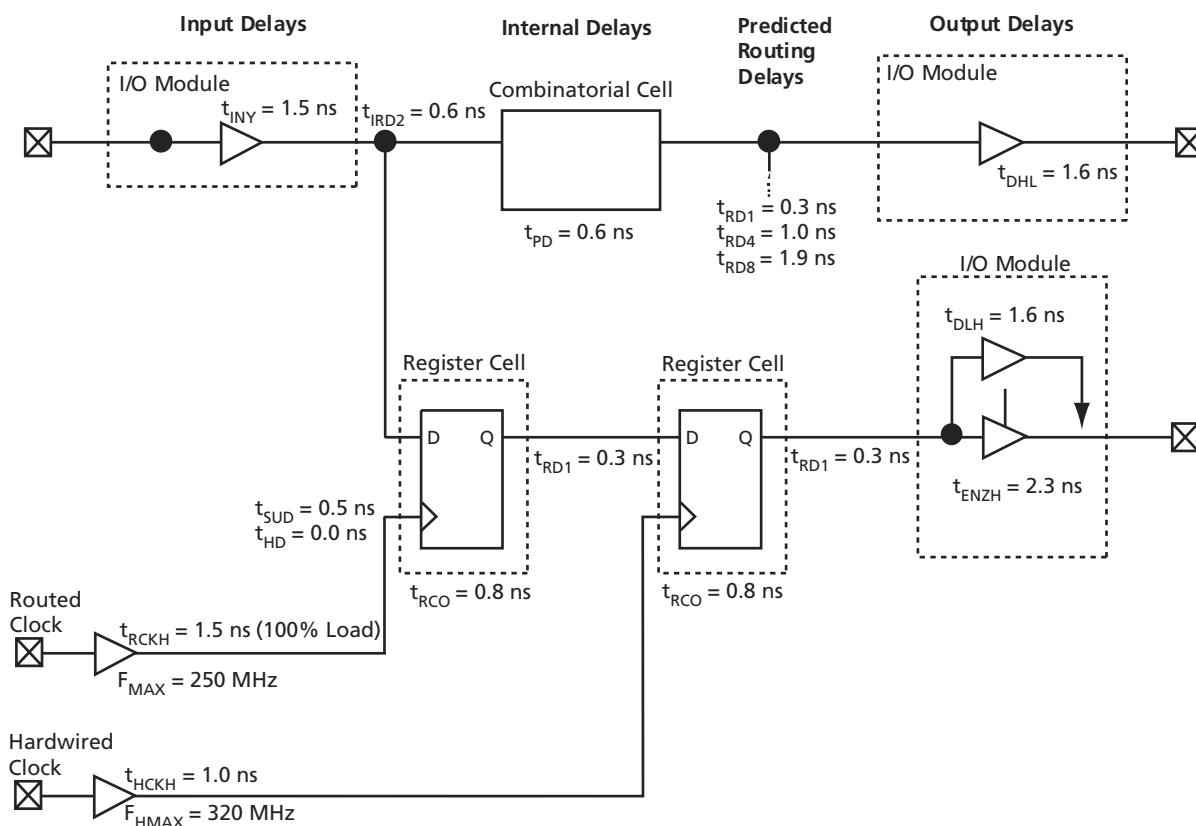
EQ 1-3

$$I_{OL} = (256V_{CC}) \times V_{OUT} \times (V_{CC} - V_{OUT})$$

for $0 V < V_{OUT} < 0.18 V_{CC}$

EQ 1-4

SX Timing Model



Note: Values shown for A54SX08-3, worst-case commercial conditions.

Figure 1-12 • SX Timing Model

Hardwired Clock

$$\begin{aligned}\text{External Setup} &= t_{INY} + t_{IRD1} + t_{SUD} - t_{HCKH} \\ &= 1.5 + 0.3 + 0.5 - 1.0 = 1.3 \text{ ns}\end{aligned}$$
EQ 1-15

Clock-to-Out (Pin-to-Pin)

$$\begin{aligned}&= t_{HCKH} + t_{RCO} + t_{RD1} + t_{DHL} \\ &= 1.0 + 0.8 + 0.3 + 1.6 = 3.7 \text{ ns}\end{aligned}$$
EQ 1-16

Routed Clock

$$\begin{aligned}\text{External Setup} &= t_{INY} + t_{IRD1} + t_{SUD} - t_{RCKH} \\ &= 1.5 + 0.3 + 0.5 - 1.5 = 0.8 \text{ ns}\end{aligned}$$
EQ 1-17

Clock-to-Out (Pin-to-Pin)

$$\begin{aligned}&= t_{RCKH} + t_{RCO} + t_{RD1} + t_{DHL} \\ &= 1.52 + 0.8 + 0.3 + 1.6 = 4.2 \text{ ns}\end{aligned}$$
EQ 1-18

Table 1-17 • A54SX08 Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75$ V, $V_{CCA}, V_{CCI} = 3.0$ V, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t_{HCKH}	Input LOW to HIGH (pad to R-Cell input)	1.0		1.1		1.3		1.5		ns
t_{HCKL}	Input HIGH to LOW (pad to R-Cell input)	1.0		1.2		1.4		1.6		ns
t_{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t_{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t_{HCKSW}	Maximum Skew	0.1		0.2		0.2		0.2		ns
t_{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f_{HMAX}	Maximum Frequency	350		320		280		240		MHz
Routed Array Clock Networks										
t_{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)	1.3		1.5		1.7		2.0		ns
t_{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell Input)	1.4		1.6		1.8		2.1		ns
t_{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)	1.4		1.7		1.9		2.2		ns
t_{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)	1.5		1.7		2.0		2.3		ns
t_{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)	1.5		1.7		1.9		2.2		ns
t_{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)	1.5		1.8		2.0		2.3		ns
t_{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t_{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t_{RCKSW}	Maximum Skew (light load)	0.1		0.2		0.2		0.2		ns
t_{RCKSW}	Maximum Skew (50% load)	0.3		0.3		0.4		0.4		ns
t_{RCKSW}	Maximum Skew (100% load)	0.3		0.3		0.4		0.4		ns
TTL Output Module Timing1										
t_{DLH}	Data-to-Pad LOW to HIGH	1.6		1.9		2.1		2.5		ns
t_{DHL}	Data-to-Pad HIGH to LOW	1.6		1.9		2.1		2.5		ns
t_{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.8		3.2		ns
t_{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.1		3.6		ns
t_{ENLZ}	Enable-to-Pad, L to Z	1.4		1.7		1.9		2.2		ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A54SX16 Timing Characteristics

Table 1-18 • A54SX16 Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75$ V, $V_{CCA}, V_{CCI} = 3.0$ V, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays¹										
t_{PD}	Internal Array Module	0.6		0.7		0.8		0.9		ns
Predicted Routing Delays²										
t_{RD1}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t_{RD2}	FO = 1 Routing Delay, Fast Connect	0.3		0.4		0.4		0.5		ns
t_{RD3}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t_{RD4}	FO = 2 Routing Delay	0.6		0.7		0.8		0.9		ns
t_{RD8}	FO = 3 Routing Delay	0.8		0.9		1.0		1.2		ns
t_{RD12}	FO = 4 Routing Delay	1.0		1.2		1.4		1.6		ns
t_{RD16}	FO = 8 Routing Delay	1.9		2.2		2.5		2.9		ns
t_{RD32}	FO = 12 Routing Delay	2.8		3.2		3.7		4.3		ns
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q	0.8		1.1		1.2		1.4		ns
t_{CLR}	Asynchronous Clear-to-Q	0.5		0.6		0.7		0.8		ns
t_{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.9		1.0		ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.5		0.5		0.7		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t_{INYH}	Input Data Pad-to-Y HIGH	1.5		1.7		1.9		2.2		ns
t_{INYL}	Input Data Pad-to-Y LOW	1.5		1.7		1.9		2.2		ns
Predicted Input Routing Delays²										
t_{IRD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t_{IRD2}	FO = 2 Routing Delay	0.6		0.7		0.8		0.9		ns
t_{IRD3}	FO = 3 Routing Delay	0.8		0.9		1.0		1.2		ns
t_{IRD4}	FO = 4 Routing Delay	1.0		1.2		1.4		1.6		ns
t_{IRD8}	FO = 8 Routing Delay	1.9		2.2		2.5		2.9		ns
t_{IRD12}	FO = 12 Routing Delay	2.8		3.2		3.7		4.3		ns

Notes:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} , the loading is 5 pF.

Table 1-18 • A54SX16 Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75$ V, $V_{CCA}, V_{CCI} = 3.0$ V, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t_{HCKH}	Input LOW to HIGH (pad to R-Cell input)	1.2		1.4		1.5		1.8		ns
t_{HCKL}	Input HIGH to LOW (pad to R-Cell input)	1.2		1.4		1.6		1.9		ns
t_{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t_{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t_{HCKSW}	Maximum Skew		0.2		0.2		0.3		0.3	ns
t_{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f_{HMAX}	Maximum Frequency		350		320		280		240	MHz
Routed Array Clock Networks										
t_{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)	1.6		1.8		2.1		2.5		ns
t_{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell input)	1.8		2.0		2.3		2.7		ns
t_{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)	1.8		2.1		2.5		2.8		ns
t_{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t_{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)	1.8		2.1		2.4		2.8		ns
t_{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t_{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t_{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t_{RCKSW}	Maximum Skew (light load)		0.5		0.5		0.5		0.7	ns
t_{RCKSW}	Maximum Skew (50% load)		0.5		0.6		0.7		0.8	ns
t_{RCKSW}	Maximum Skew (100% load)		0.5		0.6		0.7		0.8	ns
TTL Output Module Timing³										
t_{DLH}	Data-to-Pad LOW to HIGH	1.6		1.9		2.1		2.5		ns
t_{DHL}	Data-to-Pad HIGH to LOW	1.6		1.9		2.1		2.5		ns
t_{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.8		3.2		ns
t_{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.1		3.6		ns
t_{ENLZ}	Enable-to-Pad, L to Z	1.4		1.7		1.9		2.2		ns
t_{ENHZ}	Enable-to-Pad, H to Z	1.3		1.5		1.7		2.0		ns

Notes:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENLZ} and t_{ENZH} . For t_{ENLZ} and t_{ENZH} , the loading is 5 pF.

Table 1-19 • A54SX16P Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75$ V, $V_{CCA}, V_{CCI} = 3.0$ V, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL/PCI Output Module Timing										
t_{DLH}	Data-to-Pad LOW to HIGH	1.5		1.7		2.0		2.3		ns
t_{DHL}	Data-to-Pad HIGH to LOW		1.9		2.2		2.4		2.9	ns
t_{ENLZ}	Enable-to-Pad, Z to L		2.3		2.6		3.0		3.5	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.5		1.7		1.9		2.3	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.7		3.1		3.5		4.1	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.9		3.3		3.7		4.4	ns
PCI Output Module Timing³										
t_{DLH}	Data-to-Pad LOW to HIGH	1.8		2.0		2.3		2.7		ns
t_{DHL}	Data-to-Pad HIGH to LOW		1.7		2.0		2.2		2.6	ns
t_{ENLZ}	Enable-to-Pad, Z to L		0.8		1.0		1.1		1.3	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.2		1.2		1.5		1.8	ns
t_{ENLZ}	Enable-to-Pad, L to Z		1.0		1.1		1.3		1.5	ns
t_{ENHZ}	Enable-to-Pad, H to Z		1.1		1.3		1.5		1.7	ns
TTL Output Module Timing										
t_{DLH}	Data-to-Pad LOW to HIGH	2.1		2.5		2.8		3.3		ns
t_{DHL}	Data-to-Pad HIGH to LOW		2.0		2.3		2.6		3.1	ns
t_{ENLZ}	Enable-to-Pad, Z to L		2.5		2.9		3.2		3.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.0		3.5		3.9		4.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.3		2.7		3.1		3.6	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.9		3.3		3.7		4.4	ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 10 pF loading.

Table 1-20 • A54SX32 Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75$ V, $V_{CCA}, V_{CCI} = 3.0$ V, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t_{HCKH}	Input LOW to HIGH (pad to R-Cell input)		1.9		2.1		2.4		2.8	ns
t_{HCKL}	Input HIGH to LOW (pad to R-Cell input)		1.9		2.1		2.4		2.8	ns
t_{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t_{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t_{HCKSW}	Maximum Skew		0.3		0.4		0.4		0.5	ns
t_{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f_{HMAX}	Maximum Frequency		350		320		280		240	MHz
Routed Array Clock Networks										
t_{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)		2.4		2.7		3.0		3.5	ns
t_{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell input)		2.4		2.7		3.1		3.6	ns
t_{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)		2.7		3.0		3.5		4.1	ns
t_{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)		2.7		3.1		3.6		4.2	ns
t_{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)		2.7		3.1		3.5		4.1	ns
t_{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)		2.8		3.2		3.6		4.3	ns
t_{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t_{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t_{RCKSW}	Maximum Skew (light load)		0.85		0.98		1.1		1.3	ns
t_{RCKSW}	Maximum Skew (50% load)		1.23		1.4		1.6		1.9	ns
t_{RCKSW}	Maximum Skew (100% load)		1.30		1.5		1.7		2.0	ns
TTL Output Module Timing³										
t_{DLH}	Data-to-Pad LOW to HIGH		1.6		1.9		2.1		2.5	ns
t_{DHL}	Data-to-Pad HIGH to LOW		1.6		1.9		2.1		2.5	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.8		3.2	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.3		2.7		3.1		3.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z		1.4		1.7		1.9		2.2	ns
t_{ENHZ}	Enable-to-Pad, H to Z		1.3		1.5		1.7		2.0	ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENLZ} and t_{ENZH} . For t_{ENLZ} and t_{ENZH} the loading is 5 pF.

Pin Description

CLKA/B	Clock A and B	TCK	Test Clock
These pins are 3.3 V / 5.0 V PCI/TTL clock inputs for clock distribution networks. The clock input is buffered prior to clocking the R-cells. If not used, this pin must be set LOW or HIGH on the board. It must not be left floating. (For A54SX72A, these clocks can be configured as bidirectional.)			Test clock input for diagnostic probe and device programming. In flexible mode, TCK becomes active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.
GND	Ground	TDI	Test Data Input
LOW supply voltage.			Serial input for boundary scan testing and diagnostic probe. In flexible mode, TDI is active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.
HCLK	Dedicated (hardwired) Array Clock	TDO	Test Data Output
This pin is the 3.3 V / 5.0 V PCI/TTL clock input for sequential modules. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. If not used, this pin must be set LOW or HIGH on the board. It must not be left floating.			Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.
I/O	Input/Output	TMS	Test Mode Select
The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTL, 3.3 V PCI or 5.0 V PCI specifications. Unused I/O pins are automatically tristated by the Designer Series software.			The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-2 on page 1-6). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.
NC	No Connection	V_{CC1}	Supply Voltage
This pin is not connected to circuitry within the device.			Supply voltage for I/Os. See Table 1-1 on page 1-5.
PRA, I/O	Probe A	V_{CCA}	Supply Voltage
The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.			Supply voltage for Array. See Table 1-1 on page 1-5.
PRB, I/O	Probe B	V_{CCR}	Supply Voltage
The Probe B pin is used to output data from any node within the device. This diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.			Supply voltage for input tolerance (required for internal biasing). See Table 1-1 on page 1-5.

Package Pin Assignments

84-Pin PLCC

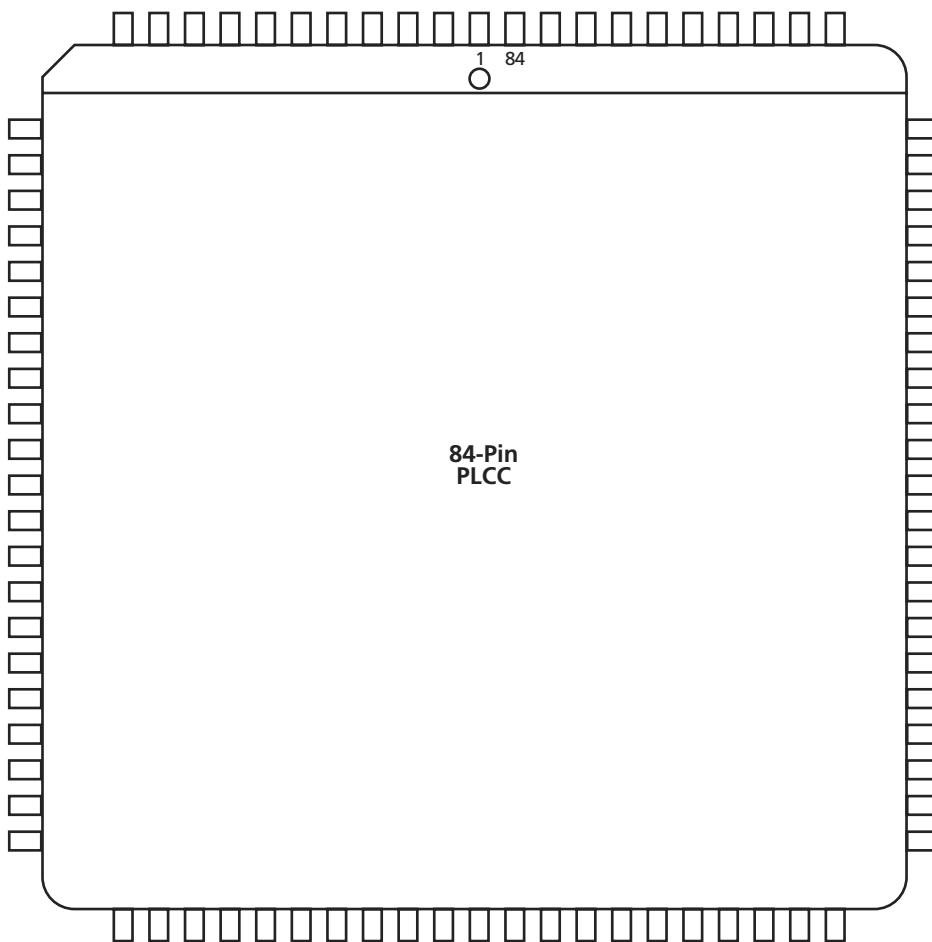


Figure 2-1 • 84-Pin PLCC (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	NC	I/O	I/O
5	I/O	I/O	I/O
6	NC	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	I/O	I/O	I/O
11	TMS	TMS	TMS
12	V _{CCI}	V _{CCI}	V _{CCI}
13	I/O	I/O	I/O
14	NC	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	NC	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	NC	I/O	I/O
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	NC	I/O	I/O
24	I/O	I/O	I/O
25	V _{CCR}	V _{CCR}	V _{CCR}
26	GND	GND	GND
27	V _{CCA}	V _{CCA}	V _{CCA}
28	GND	GND	GND
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	NC	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	NC	I/O	I/O
36	I/O	I/O	I/O

Note: * Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	NC	I/O	I/O
40	V _{CCI}	V _{CCI}	V _{CCI}
41	V _{CCA}	V _{CCA}	V _{CCA}
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	I/O	I/O	I/O
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	NC	I/O	I/O
49	I/O	I/O	I/O
50	NC	I/O	I/O
51	I/O	I/O	I/O
52	GND	GND	GND
53	I/O	I/O	I/O
54	I/O	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	I/O	I/O	I/O
58	I/O	I/O	I/O
59	I/O	I/O	I/O
60	V _{CCI}	V _{CCI}	V _{CCI}
61	NC	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	NC	I/O	I/O
65*	I/O	I/O	NC*
66	I/O	I/O	I/O
67	NC	I/O	I/O
68	I/O	I/O	I/O
69	I/O	I/O	I/O
70	NC	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
145	V _{CCA}	V _{CCA}	V _{CCA}
146	GND	GND	GND
147	I/O	I/O	I/O
148	V _{CCI}	V _{CCI}	V _{CCI}
149	I/O	I/O	I/O
150	I/O	I/O	I/O
151	I/O	I/O	I/O
152	I/O	I/O	I/O
153	I/O	I/O	I/O
154	I/O	I/O	I/O
155	NC	I/O	I/O
156	NC	I/O	I/O
157	GND	GND	GND
158	I/O	I/O	I/O
159	I/O	I/O	I/O
160	I/O	I/O	I/O
161	I/O	I/O	I/O
162	I/O	I/O	I/O
163	I/O	I/O	I/O
164	V _{CCI}	V _{CCI}	V _{CCI}
165	I/O	I/O	I/O
166	I/O	I/O	I/O
167	NC	I/O	I/O
168	I/O	I/O	I/O
169	I/O	I/O	I/O
170	NC	I/O	I/O
171	I/O	I/O	I/O
172	I/O	I/O	I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	NC	I/O	I/O
177	I/O	I/O	I/O
178	I/O	I/O	I/O
179	I/O	I/O	I/O
180	CLKA	CLKA	CLKA

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
181	CLKB	CLKB	CLKB
182	V _{CCR}	V _{CCR}	V _{CCR}
183	GND	GND	GND
184	V _{CCA}	V _{CCA}	V _{CCA}
185	GND	GND	GND
186	PRA, I/O	PRA, I/O	PRA, I/O
187	I/O	I/O	I/O
188	I/O	I/O	I/O
189	NC	I/O	I/O
190	I/O	I/O	I/O
191	I/O	I/O	I/O
192	NC	I/O	I/O
193	I/O	I/O	I/O
194	I/O	I/O	I/O
195	NC	I/O	I/O
196	I/O	I/O	I/O
197	I/O	I/O	I/O
198	NC	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	V _{CCI}	V _{CCI}	V _{CCI}
202	NC	I/O	I/O
203	NC	I/O	I/O
204	I/O	I/O	I/O
205	NC	I/O	I/O
206	I/O	I/O	I/O
207	I/O	I/O	I/O
208	TCK, I/O	TCK, I/O	TCK, I/O

Note: * Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

144-Pin TQFP

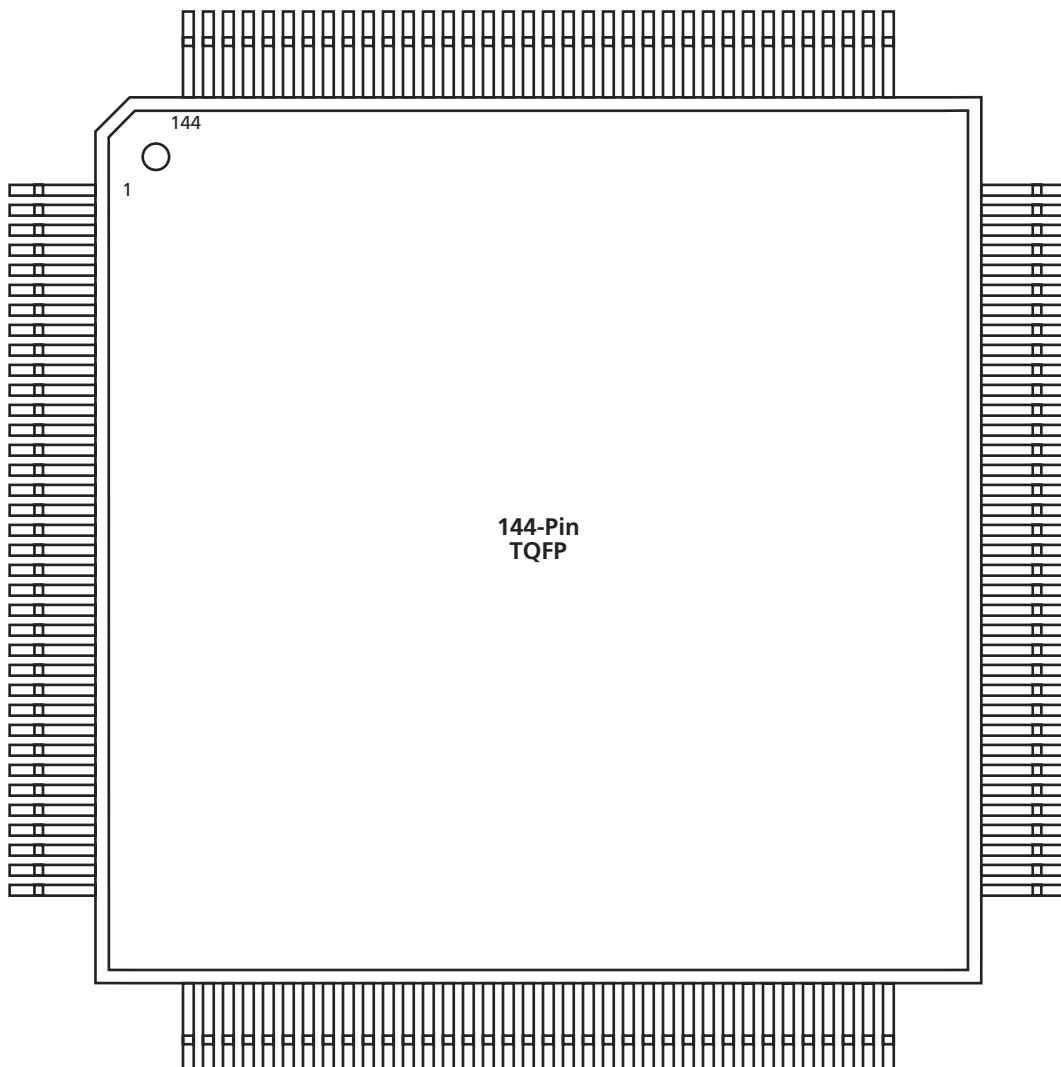


Figure 2-3 • 144-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	NC	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	TMS	TMS	TMS
11	V _{CCI}	V _{CCI}	V _{CCI}
12	NC	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O
21	GND	GND	GND
22	V _{CCA}	V _{CCA}	V _{CCA}
23	GND	GND	GND
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	I/O	I/O	I/O
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	V _{CCI}	V _{CCI}	V _{CCI}
33	V _{CCA}	V _{CCA}	V _{CCA}
34	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	NC	I/O	I/O
41	I/O	I/O	I/O
42	NC	I/O	I/O
43	I/O	I/O	I/O
44	GND	GND	GND
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	V _{CCI}	V _{CCI}	V _{CCI}
53	I/O	I/O	I/O
54	NC	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	NC	I/O	I/O
58	I/O	I/O	I/O
59	I/O	I/O	I/O
60	I/O	I/O	I/O
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	PRB, I/O	PRB, I/O	PRB, I/O
65	GND	GND	GND
66	V _{CCA}	V _{CCA}	V _{CCA}
67	V _{CCR}	V _{CCR}	V _{CCR}
68	I/O	I/O	I/O

329-Pin PBGA	
Pin Number	A54SX32 Function
D3	I/O
D4	TCK, I/O
D5	I/O
D6	I/O
D7	I/O
D8	I/O
D9	I/O
D10	I/O
D11	V _{CCA}
D12	V _{CCR}
D13	I/O
D14	I/O
D15	I/O
D16	I/O
D17	I/O
D18	I/O
D19	I/O
D20	I/O
D21	I/O
D22	I/O
D23	I/O
E1	V _{CCI}
E2	I/O
E3	I/O
E4	I/O
E20	I/O
E21	I/O
E22	I/O
E23	I/O
F1	I/O
F2	TMS
F3	I/O
F4	I/O
F20	I/O
F21	I/O

329-Pin PBGA	
Pin Number	A54SX32 Function
F22	I/O
F23	I/O
G1	I/O
G2	I/O
G3	I/O
G4	I/O
G20	I/O
G21	I/O
G22	I/O
G23	GND
H1	I/O
H2	I/O
H3	I/O
H4	I/O
H20	V _{CCA}
H21	I/O
H22	I/O
H23	I/O
J1	NC
J2	I/O
J3	I/O
J4	I/O
J20	I/O
J21	I/O
J22	I/O
J23	I/O
K1	I/O
K2	I/O
K3	I/O
K4	I/O
K10	GND
K11	GND
K12	GND
K13	GND
K14	GND

329-Pin PBGA	
Pin Number	A54SX32 Function
K20	I/O
K21	I/O
K22	I/O
K23	I/O
L1	I/O
L2	I/O
L3	I/O
L4	V _{CCR}
L10	GND
L11	GND
L12	GND
L13	GND
L14	GND
L20	V _{CCR}
L21	I/O
L22	I/O
L23	NC
M1	I/O
M2	I/O
M3	I/O
M4	V _{CCA}
M10	GND
M11	GND
M12	GND
M13	GND
M14	GND
M20	V _{CCA}
M21	I/O
M22	I/O
M23	V _{CCI}
N1	I/O
N2	I/O
N3	I/O
N4	I/O
N10	GND

329-Pin PBGA	
Pin Number	A54SX32 Function
N11	GND
N12	GND
N13	GND
N14	GND
N20	NC
N21	I/O
N22	I/O
N23	I/O
P1	I/O
P2	I/O
P3	I/O
P4	I/O
P10	GND
P11	GND
P12	GND
P13	GND
P14	GND
P20	I/O
P21	I/O
P22	I/O
P23	I/O
R1	I/O
R2	I/O
R3	I/O
R4	I/O
R20	I/O
R21	I/O
R22	I/O
R23	I/O
T1	I/O
T2	I/O
T3	I/O
T4	I/O
T20	I/O
T21	I/O

144-Pin FBGA	
Pin Number	A54SX08 Function
A1	I/O
A2	I/O
A3	I/O
A4	I/O
A5	V _{CCA}
A6	GND
A7	CLKA
A8	I/O
A9	I/O
A10	I/O
A11	I/O
A12	I/O
B1	I/O
B2	GND
B3	I/O
B4	I/O
B5	I/O
B6	I/O
B7	CLKB
B8	I/O
B9	I/O
B10	I/O
B11	GND
B12	I/O
C1	I/O
C2	I/O
C3	TCK, I/O
C4	I/O
C5	I/O
C6	PRA, I/O
C7	I/O
C8	I/O
C9	I/O
C10	I/O
C11	I/O
C12	I/O

144-Pin FBGA	
Pin Number	A54SX08 Function
D1	I/O
D2	V _{CCI}
D3	TDI, I/O
D4	I/O
D5	I/O
D6	I/O
D7	I/O
D8	I/O
D9	I/O
D10	I/O
D11	I/O
D12	I/O
E1	I/O
E2	I/O
E3	I/O
E4	I/O
E5	TMS
E6	V _{CCI}
E7	V _{CCI}
E8	V _{CCI}
E9	V _{CCA}
E10	I/O
E11	GND
E12	I/O
F1	I/O
F2	I/O
F3	V _{CCR}
F4	I/O
F5	GND
F6	GND
F7	GND
F8	V _{CCI}
F9	I/O
F10	GND
F11	I/O
F12	I/O

144-Pin FBGA	
Pin Number	A54SX08 Function
G1	I/O
G2	GND
G3	I/O
G4	I/O
G5	GND
G6	GND
G7	GND
G8	V _{CCI}
G9	I/O
G10	I/O
G11	I/O
G12	I/O
H1	I/O
H2	I/O
H3	I/O
H4	I/O
H5	V _{CCA}
H6	V _{CCA}
H7	V _{CCI}
H8	V _{CCI}
H9	V _{CCA}
H10	I/O
H11	I/O
H12	V _{CCR}
J1	I/O
J2	I/O
J3	I/O
J4	I/O
J5	I/O
J6	PRB, I/O
J7	I/O
J8	I/O
J9	I/O
J10	I/O
J11	I/O
J12	V _{CCA}

144-Pin FBGA	
Pin Number	A54SX08 Function
K1	I/O
K2	I/O
K3	I/O
K4	I/O
K5	I/O
K6	I/O
K7	GND
K8	I/O
K9	I/O
K10	GND
K11	I/O
K12	I/O
L1	GND
L2	I/O
L3	I/O
L4	I/O
L5	I/O
L6	I/O
L7	HCLK
L8	I/O
L9	I/O
L10	I/O
L11	I/O
L12	I/O
M1	I/O
M2	I/O
M3	I/O
M4	I/O
M5	I/O
M6	I/O
M7	V _{CCA}
M8	I/O
M9	I/O
M10	I/O
M11	TDO, I/O
M12	I/O